

**This Page Is Inserted by IFW Operations  
and is not a part of the Official Record**

## **BEST AVAILABLE IMAGES**

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

**IMAGES ARE BEST AVAILABLE COPY.**

**As rescanning documents *will not* correct images,  
please do not report the images to the  
Image Problem Mailbox.**

0500298-1504

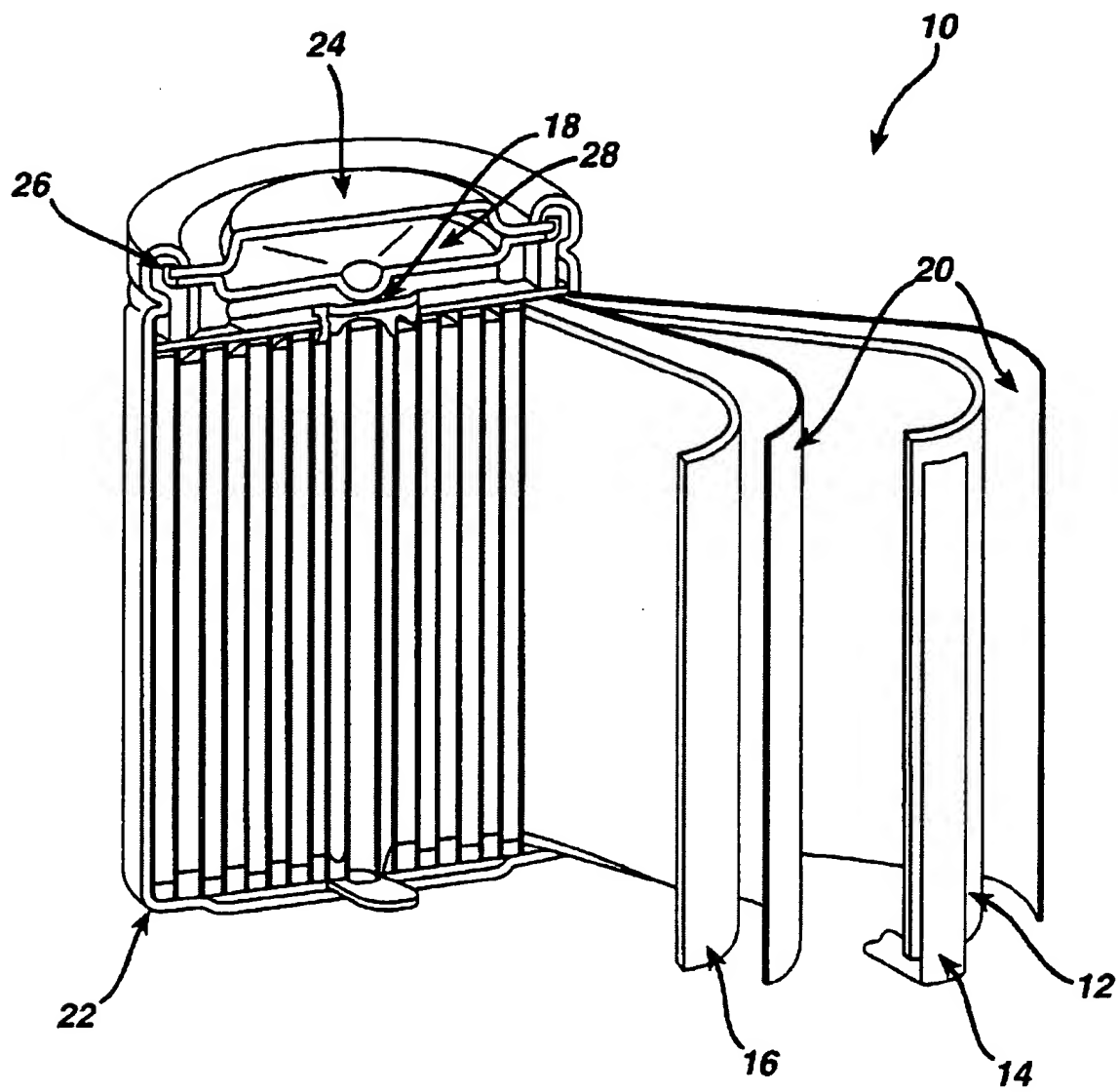


FIG. 1

The figure displays three stacked X-ray diffraction (XRD) patterns. The y-axis represents Intensity in Counts, ranging from 0 to 4500. The x-axis represents the diffraction angle 2θ in degrees, ranging from 10 to 70. The top pattern, labeled λ-MnO<sub>2</sub>, 16 hrs, shows a sharp peak at approximately 18.8° 2θ and a broad peak at approximately 44.5° 2θ. The middle pattern, labeled λ-MnO<sub>2</sub>, 0.75 hrs, shows a sharp peak at approximately 18.8° 2θ and a broad peak at approximately 44.5° 2θ. The bottom pattern, labeled LiMn<sub>2</sub>O<sub>4</sub> spinel, shows a sharp peak at approximately 18.8° 2θ and a broad peak at approximately 44.5° 2θ. The patterns are vertically offset for clarity.

**FIG. 2**

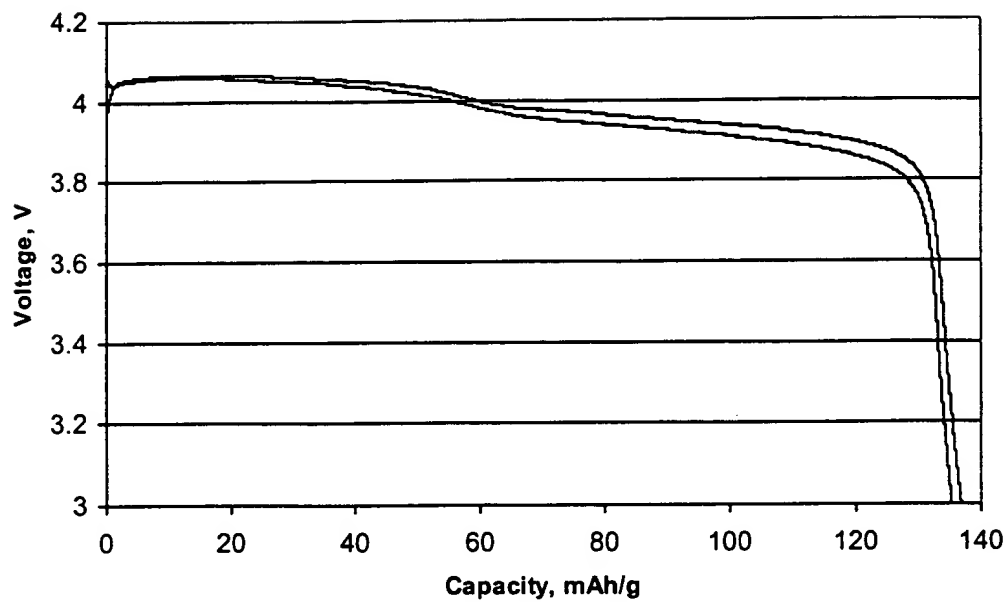
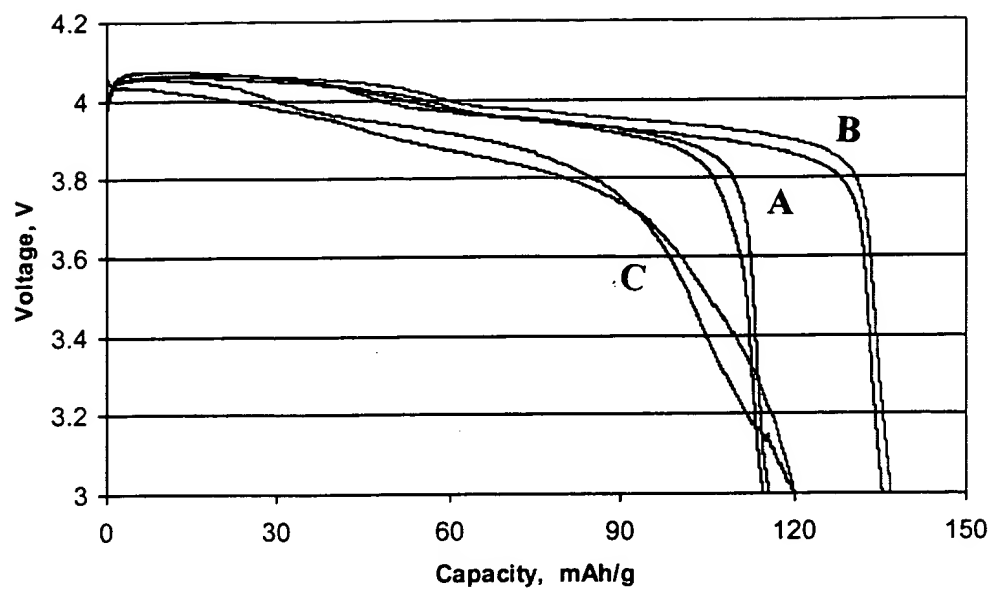


FIG. 3



**FIG. 4**

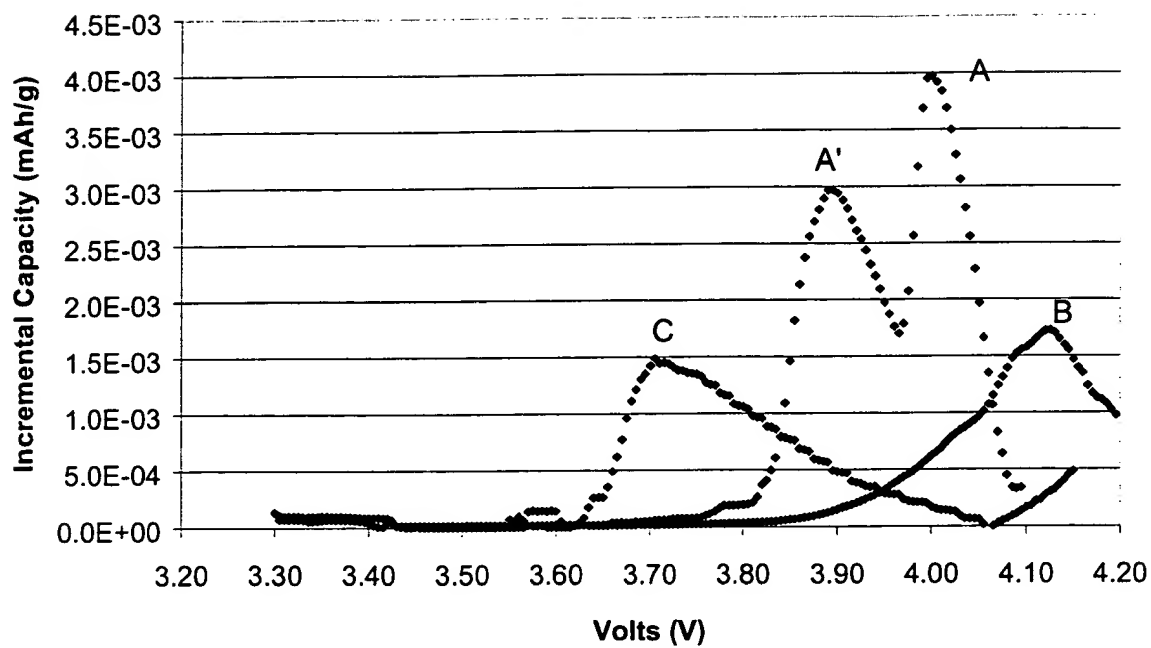


FIG. 5

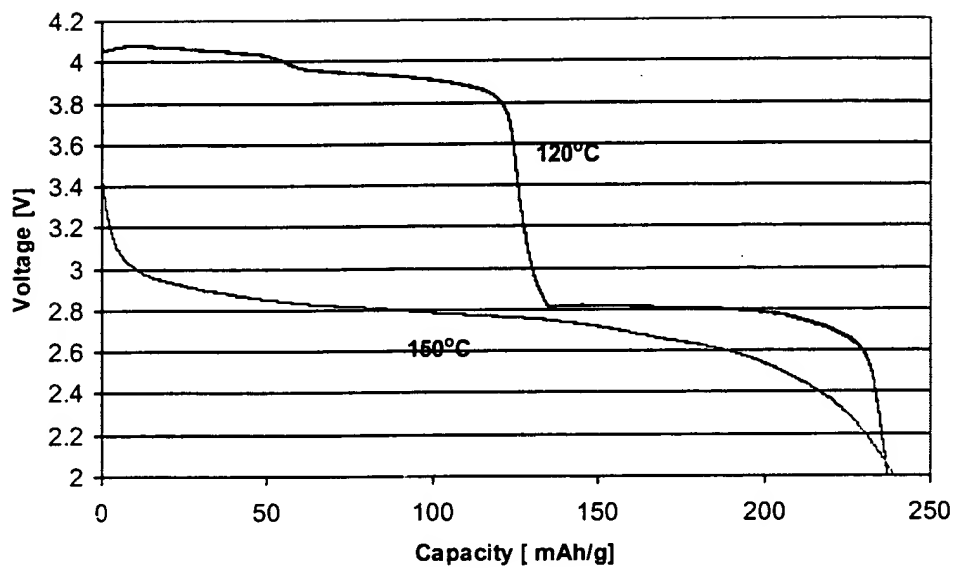


FIG. 6